

FEATURES:

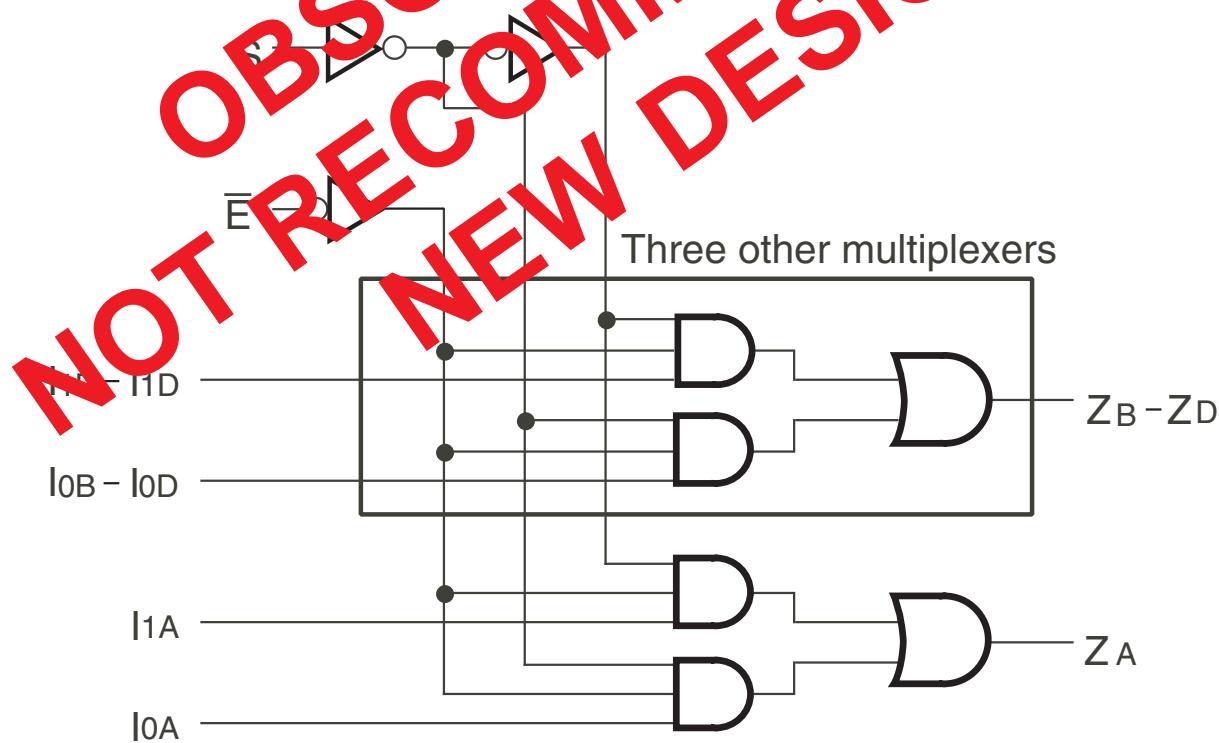
- A, C, and D grades
- Low input and output leakage $\leq 1\mu\text{A}$ (max.)
- CMOS power levels
- True TTL input and output compatibility:
 - $V_{OH} = 3.3\text{V}$ (typ.)
 - $V_{OL} = 0.3\text{V}$ (typ.)
- High Drive outputs (-15mA I_{OH} , 48mA I_{OL})
- Meets or exceeds JEDEC standard 18 specifications
- Power off disable outputs permit "live insertion"
- Available in SOIC and QSOP packages

DESCRIPTION:

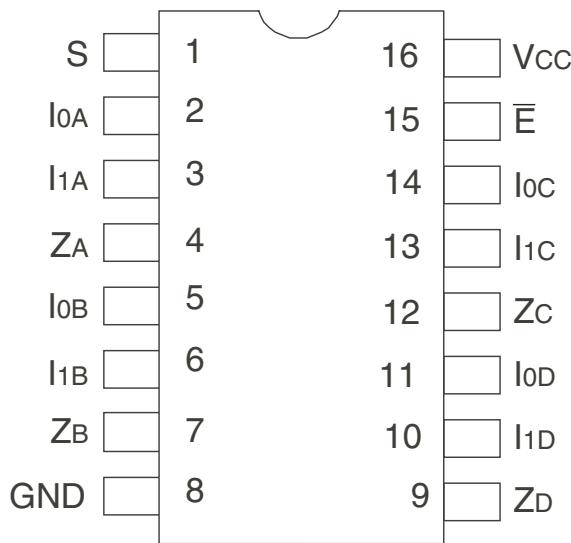
The FCT157T is a high-speed quad 2-input multiplexer built using an advanced dual metal CMOS technology. Four bits of data from two sources can be selected using the common select input. The four buffered outputs present the selected data in the true (non-inverting) form.

The FCT157T has a common, active-low, enable input. When the enable input is not active, all four outputs are held low. A common application of FCT157T is to move data from two different groups of registers to a common bus. Another application is as a function generator. The FCT157T can generate any four of the 16 different functions of two variables with one variable common.

FUNCTIONAL BLOCK DIAGRAM



PIN CONFIGURATION

SOIC/ QSOP
TOP VIEWABSOLUTE MAXIMUM RATINGS⁽¹⁾

Symbol	Description	Max	Unit
V _{TERM} ⁽²⁾	Terminal Voltage with Respect to GND	-0.5 to +7	V
V _{TERM} ⁽³⁾	Terminal Voltage with Respect to GND	-0.5 to V _{CC} +0.5	V
T _{STG}	Storage Temperature	-65 to +150	°C
I _{OUT}	DC Output Current	-60 to +120	mA

NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability. No terminal voltage may exceed V_{CC} by +0.5V unless otherwise noted.
- Inputs and V_{CC} terminals only.
- Output and I/O terminals only.

CAPACITANCE (T_A = +25°C, F = 1.0MHz)

Symbol	Parameter ⁽¹⁾	Conditions	Typ.	Max.	Unit
C _{IN}	Input Capacitance	V _{IN} = 0V	6	10	pF
C _{OUT}	Output Capacitance	V _{OUT} = 0V	8	12	pF

NOTE:

- This parameter is measured at characterization but not tested.

PIN DESCRIPTION

Pin Names	Description
I _{0A} - I _{0D}	Source 0 Data Inputs
I _{1A} - I _{1D}	Source 1 Data Inputs
Ē	Enable Input (Active LOW)
S	Select Input
Z _A - Z _D	Outputs

FUNCTION TABLE⁽¹⁾

Inputs				Outputs
Ē	S	I ₀	I ₁	Z _x
H	X	X	X	L
L	H	X	L	L
L	H	X	H	H
L	L	L	X	L
L	L	H	X	H

NOTE:

- H = HIGH Voltage Level
- X = Don't Care
- L = LOW Voltage Level
- Z = High Impedance

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Industrial: $T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$, $V_{CC} = 5.0\text{V} \pm 5\%$

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
V_{IH}	Input HIGH Level	Guaranteed Logic HIGH Level		2	—	—	V
V_{IL}	Input LOW Level	Guaranteed Logic LOW Level		—	—	0.8	V
I_{IH}	Input HIGH Current ⁽⁴⁾	$V_{CC} = \text{Max.}$	$V_I = 2.7\text{V}$	—	—	± 1	μA
I_{IL}	Input LOW Current ⁽⁴⁾	$V_{CC} = \text{Max.}$	$V_I = 0.5\text{V}$	—	—	± 1	μA
I_{OZH}	High Impedance Output Current ⁽⁴⁾	$V_{CC} = \text{Max.}, V_I = V_{CC} (\text{Max.})$	$V_I = 2.7\text{V}$	—	—	± 1	μA
I_{OZL}			$V_I = 0.5\text{V}$	—	—	± 1	
I_I	Input HIGH Current ⁽⁴⁾	$V_{CC} = \text{Max.}, V_I = V_{CC} (\text{Max.})$		—	—	± 1	μA
V_{IK}	Clamp Diode Voltage	$V_{CC} = \text{Min.}, I_{IN} = -18\text{mA}$		—	-0.7	-1.2	V
V_H	Input Hysteresis	—		—	200	—	mV
I_{CC}	Quiescent Power Supply Current	$V_{CC} = \text{Max.}$ $V_{IN} = \text{GND or } V_{CC}$		—	0.01	1	mA

OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
V_{OH}	Output HIGH Voltage	$V_{CC} = \text{Min}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -8\text{mA}$	2.4	3.3	—	V
			$I_{OH} = -15\text{mA}$	2	3	—	
V_{OL}	Output LOW Voltage	$V_{CC} = \text{Min}$ $V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 48\text{mA}$	—	0.3	0.5	V
I_{OS}	Short Circuit Current	$V_{CC} = \text{Max.}, V_O = \text{GND}$ ⁽³⁾		-60	-120	-225	mA
I_{OFF}	Input/Output Power Off Leakage ⁽⁵⁾	$V_{CC} = 0\text{V}, V_{IN}$ or $V_O \leq 4.5\text{V}$		—	—	± 1	μA

NOTES:

1. For conditions shown as Min. or Max., use appropriate value specified under Electrical Characteristics for the applicable device type.
2. Typical values are at $V_{CC} = 5.0\text{V}$, $+25^\circ\text{C}$ ambient.
3. Not more than one output should be tested at one time. Duration of the test should not exceed one second.
4. The test limit for this parameter is $\pm 5\mu\text{A}$ at $T_A = -55^\circ\text{C}$.
5. This parameter is guaranteed but not tested.

POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Typ. ⁽²⁾	Max.	Unit
ΔI_{CC}	Quiescent Power Supply Current TTL Inputs HIGH	V _{CC} = Max. V _{IN} = 3.4V ⁽³⁾		—	0.5	2	mA
I_{CCD}	Dynamic Power Supply Current ⁽⁴⁾	V _{CC} = Max. Outputs Open \bar{E} = GND One Input Toggling 50% Duty Cycle	V _{IN} = V _{CC} V _{IN} = GND	—	0.15	0.25	mA/ MHz
I_C	Total Power Supply Current ⁽⁶⁾	V _{CC} = Max. Outputs Open $f_O = 10\text{MHz}$	V _{IN} = V _{CC} V _{IN} = GND	—	1.5	3.5	mA
		50% Duty Cycle \bar{E} = GND One Bit Toggling	V _{IN} = 3.4V V _{IN} = GND	—	1.8	4.5	mA
		V _{CC} = Max. Outputs Open $f_O = 2.5\text{MHz}$	V _{IN} = V _{CC} V _{IN} = GND	—	1.5	3.5 ⁽⁵⁾	
		50% Duty Cycle \bar{E} = GND Four Bits Toggling	V _{IN} = 3.4V V _{IN} = GND	—	2.5	7.5 ⁽⁵⁾	

NOTES:

1. For conditions shown as Min. or Max., use appropriate value specified under Electrical Characteristics for the applicable device type.

2. Typical values are at $V_{CC} = 5.0\text{V}$, $+25^\circ\text{C}$ ambient.3. Per TTL driven input ($V_{IN} = 3.4\text{V}$). All other inputs at V_{CC} or GND.

4. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.

5. Values for these conditions are examples of ΔI_{CC} formula. These limits are guaranteed but not tested.6. $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$ $I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD}$ ($f_O N_O$) I_{CC} = Quiescent Current ΔI_{CC} = Power Supply Current for a TTL High Input ($V_{IN} = 3.4\text{V}$) D_H = Duty Cycle for TTL Inputs High N_T = Number of TTL Inputs at D_H I_{CCD} = Dynamic Current caused by an Input Transition Pair (HLH or LHL) f_O = Output Frequency N_O = Number of Outputs at f_O

All currents are in millamps and all frequencies are in megahertz.

SWITCHING CHARACTERISTICS OVER OPERATING RANGE

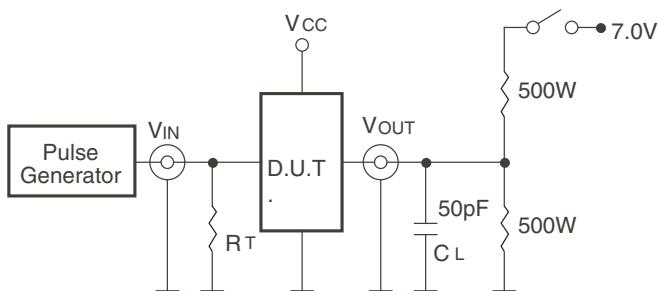
Symbol	Parameter	Condition ⁽¹⁾	IDT74FCT151AT		IDT74FCT151CT		IDT74FCT151DT		Unit
			Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	Min. ⁽²⁾	Max.	
t_{PLH}	Propagation Delay Ix to Zx	$C_L = 50\text{pF}$ $R_L = 500\Omega$	1.5	5	1.5	4.3	1.5	3.9	ns
			1.5	6	1.5	4.8	1.5	4.4	ns
			1.5	7	1.5	5.2	1.5	4.6	ns

NOTES:

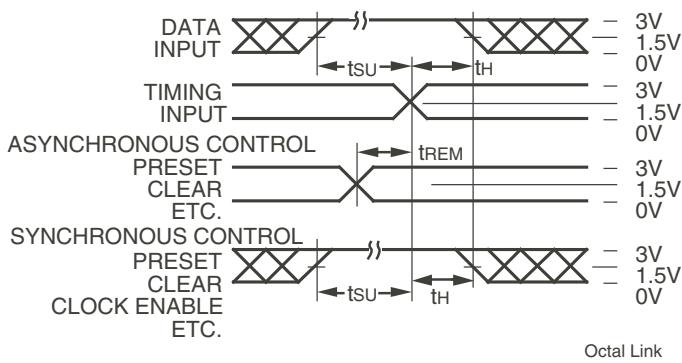
1. See test circuit and waveforms.

2. Minimum limits are guaranteed but not tested on Propagation Delays.

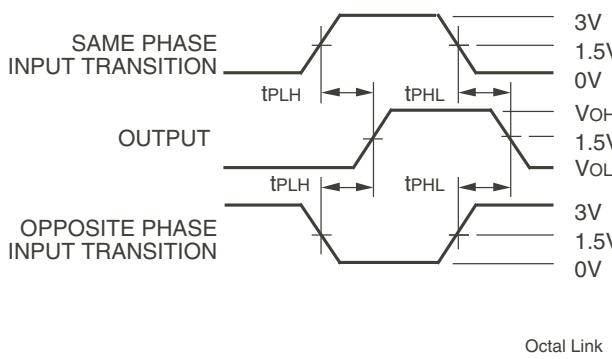
TEST CIRCUITS AND WAVEFORMS



Test Circuits for All Outputs



Set-Up, Hold, and Release Times



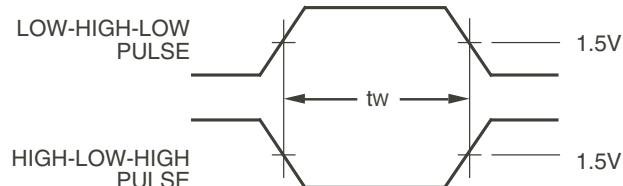
Propagation Delay

SWITCH POSITION

Test	Switch
Open Drain	Closed
Disable Low	
Enable Low	
All Other Tests	Open

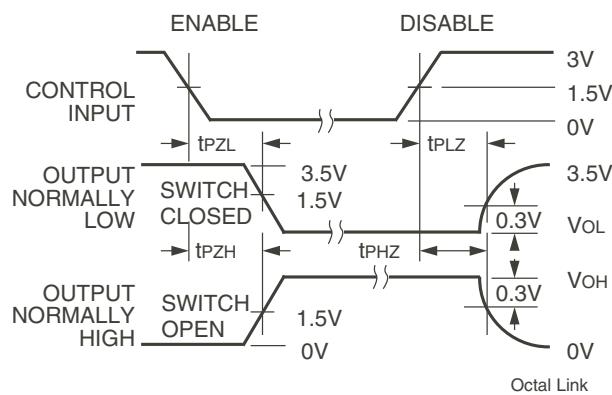
DEFINITIONS:

CL = Load capacitance: includes jig and probe capacitance.
 RT = Termination resistance: should be equal to ZOUT of the Pulse Generator.



Pulse Width

Octal Link

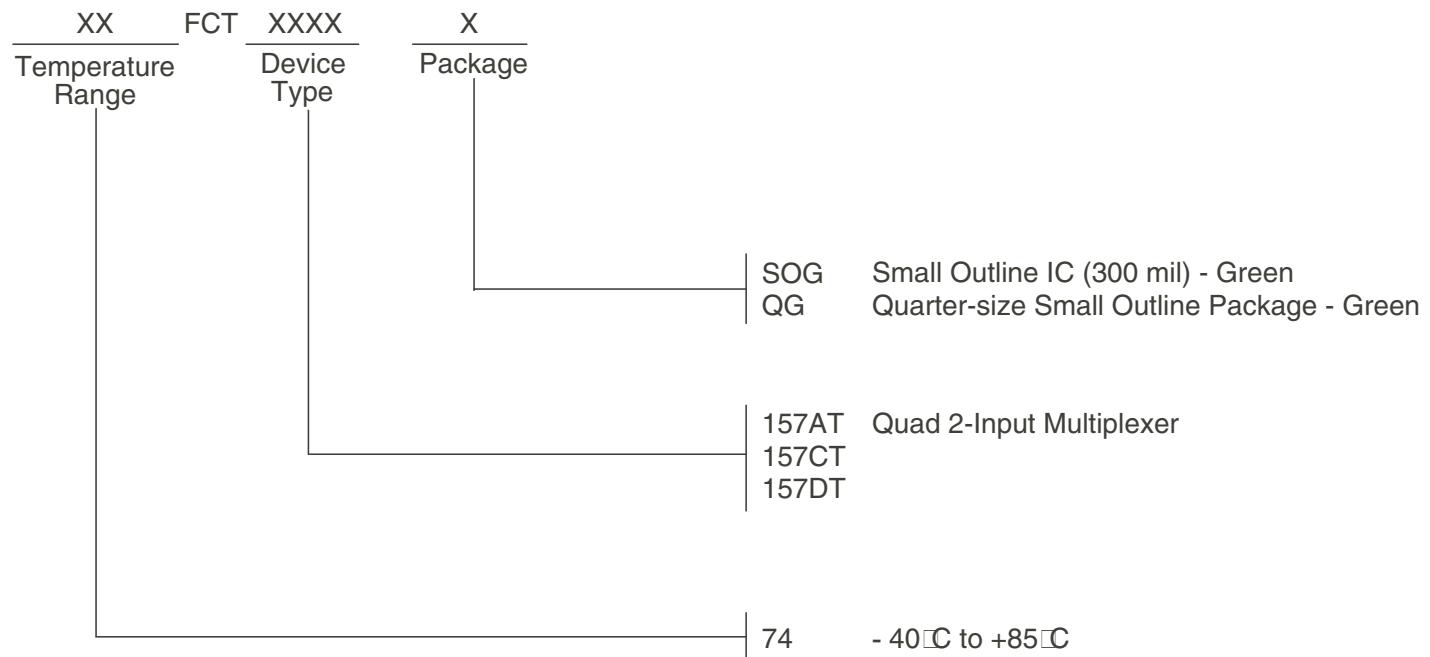


Enable and Disable Times

NOTES:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.
2. Pulse Generator for All Pulses: Rate $\leq 1.0\text{MHz}$; $t_f \leq 2.5\text{ns}$; $t_r \leq 2.5\text{ns}$.

ORDERING INFORMATION



Datasheet Document History

09/06/2009 Pg.6 Updated the ordering information by removing the "IDT" notation and non RoHS part.
01/23/2015 PDN# CQ-15-01 issued. See IDT.com for PDN specifics.
07/22/2019 Datasheet changed to Obsolete Status.

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